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Based on Form PTO-1449 (3/90)

ATTY. DOCKET NO. 455610-2590.1

SERIAL NO. 10/673,736

APPLICANT Martin MILLER et al.

FILING DATE September 29, 2003

GROUP 2117

EXAMINER: Phung M. Chung

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
IPC/	AA 5,654,987	08/05/97	Nakamura			
	AB 5,726,607	03/10/98	Brede et al			
	AC 5,825,825	10/20/98	Altmann et al			
	AD 5,900,755	05/04/99	Toeppen et al			
	AE 6,215,363	04/10/01	Conte et al			
	AF 6,295,327	09/25/01	Takla			
	AG 6,445,230	09/03/02	Rupp et al			
	AH 4,680,778	07/14/87	Krinoek			
	AI 5,943,378	08/24/99	Keba et al			
	AJ 6,188,737	02/13/01	Bruce et al			
	AK 5,914,592	06/22/99	Saito			
	AL 5,789,954	08/04/98	Toeppen et al			
IPC/	AM 4,694,244 09-15-1987	08/15/87	Whiteside et al			

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
IPC/	AN JP4105070	04/07/92	Japan			Abstract	
	AO JP5196641	08/06/93	Japan			Abstract	
	AP JP5264595	10/12/93	Japan			Abstract	
	AQ JP8220144	06/22/99	Japan			Abstract	
	AR JP9005362	01/10/97	Japan			Abstract	
	AS JP10163859	06/19/98	Japan			Abstract	
	AT JP11098876	04/09/99	Japan			Abstract	
	AU JP62003544	01/09/87	Japan			Abstract	
	AV EP 0 631 143	12/28/94	Europe			✓	
IPC/	AW EP 0 241 142	10/14/87	Europe			✓	

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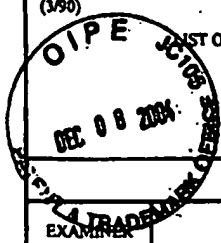
IPC/	AY	✓	Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3rd Edition, McGraw-Hill, New York, 1997, pp 229-249
	AZ	✓	<i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996
	BA	✓	HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999
	BB	✓	Infinium DCA, Agilent Technologies, March 7, 2002
IPC/	BC	✓	Communication waveform measurements, Hewlett Packard, June 26, 1996

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	AA	3 449 671	06/1969	Long Gordon D.			
	AB	3 778 550	12/1973	David et al.			
	AC	4 375 694	03/1983	Kuhn, William B.			
	AD	4 964 117	10/1990	Shier, John S.			
	AE	6 738 992 <b>922</b>	05/2004	Warwar et al.			
	AF	2004 0123208	06/2004	Miller et al.			
	AG	2004 0153883	08/2004	Miller et al.			
	AH	3, 562 710	2/9/1971	Halleck, Michael E.			
	AI	4, 100, 531	7/11/1978	Fletcher, James C.			
	AJ	5, 761, 216 A	6/2/1998	Tetsuo, Sotome <b>ET AL.</b>			
	AK	5,159,609	10/27/1992	Palicot			
	AL	5,222,101	6/22/1993	Ariyavisitakul			
	AM	5,907,587	5/25/1999	Sokoler			
	AN	6,212,246 <b>04-03-01</b>	<del>3/4/2001</del>	Hendrickson			
	AO	6,675,328	1/6/2004	Krishnamachari			
	AP	6 850 852	02/2005	Ferguson et al.			
	AQ	6 836 738	12/2004	Sepp et al.			
	AR	2002 0128787 A1	09/2002	Seng et al.			

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	AV	2002 0034337 A1	03/2002	Shekter, Jonathan Martin			
	AW	2002 0018572 A1	02/2002	Rhoads, Geoffrey B.			
	AX	6 853 696	02/2005	Moser et al.			
	AY	2001 0021151	09/2001	Verboom, Johannes et al.			
	AZ	6 463 109 B1	10/2002	McCormack et al.			
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	BB	2004 0123018 A1	06/2004	Miller et al.			
	BC	2004 0123191 A1	06/2004	Salant et al.			
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	BE	3 449 671	06/1969	Long Gordon D.			
	BF	3 778 550	12/1973	David et al.			
	BG	4 375 694	03/1983	Kuhn, William B.			
	BH	4 964 117	10/1990	Shier, John S.			
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	BL	DE 2462046 A1	11/1975	Germany			
	BM	WO 2004 032049 A2	04/2004	PCT			
	BN	GB 2 138 575 A	10/24/1984	United Kingdom			

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